CLAIMS

What is claimed is:

1	1.	A semiconductor device with ancillary electronic component comprising:
2		a semiconductor device including a first connection to a first electrical line and
3		a second connection to a second electrical line; and
4		an ancillary electronic component connected directly to the semiconductor
5		device and connected between the first connection and the second
6		connection.
1	2.	The semiconductor device of claim 1 further comprising connecting means for
2	conne	ecting the semiconductor device to a second electronic component, the connecting
3	mean	s providing clearance to accommodate the ancillary electronic component
4	betwe	een the semiconductor device and the second electronic component.
1	3.	The semiconductor device of claim 1 further comprising:
2		a plurality of electrical contact elements connected to and extending a first
3		distance from the semiconductor device;
4		the ancillary electronic component extending from the semiconductor device a
5		second distance, the second distance such that when the semiconductor
6		device is connected to a corresponding second component, the
7		ancillary electronic component will fit at least in part between the
8		semiconductor device and the corresponding second component.

1	4.	The semiconductor device of claim 3 wherein at least some of the plurality of
2	electri	cal contact elements are composite, free-standing resilient contact structures and
3	where	in said ancillary electronic component is a travel stop structure which defines a
1	minim	um separation between said semiconductor device and the corresponding
5	second	d component.

- The semiconductor device of claim 3 wherein at least some of the plurality of
 electrical contact elements are free-standing resilient contact structures primarily
 comprising a resilient material.
- 1 6. The semiconductor device of claim 1 further comprising:
 2 a second electronic component comprising in turn a plurality of electrical
 3 contact elements connected to and extending a first distance from the
 4 second electronic component, the plurality of electrical contact elements
 5 for connecting to the semiconductor device;
 6 the ancillary electronic component extending from the semiconductor device a
 5 second distance, the second distance such that when the semiconductor
- device is connected to the second electronic component, the anciliary
 electronic component will fit at least in part between the semiconductor
 device and the second electronic component.
- 7. The semiconductor device of claim 6 wherein at least some of the plurality of
 electrical contact elements are composite, free-standing resilient contact structures.

- 1 8. The semiconductor device of claim 6 wherein at least some of the plurality of
- 2 electrical contact elements are free-standing resilient contact structures primarily
- 3 comprising a resilient material.
- 1 9. The semiconductor device of claim 6 wherein the second electronic component
- 2 is a printed circuit board.
- 1 10. The semiconductor device of claim 6 wherein the second electronic component
- 2 is a socket.
- 1 11. The semiconductor device of claim 1 further comprising:
- 2 a first terminal adjoining the surface of the semiconductor device for
- 3 connecting to first circuitry of the semiconductor device;
- 4 a second terminal adjoining the surface of the semiconductor device for
- 5 connecting to second circuitry of the semiconductor device, and
- 6 wherein the ancillary electronic component is electrically connected to
- 7 the first terminal and the second terminal.
- 1 12. The semiconductor device of claim 11 wherein the ancillary electronic device is
- 2 a capacitor.
- 1 13. The semiconductor device of claim 11 wherein the first circuitry is Vdd and the
- 2 second circuitry is Vss, and the ancillary electronic device is a capacitor.

- 1 14. The semiconductor device of claim 11 wherein the second circuitry is ground.
- 1 15. The semiconductor device of claim 11 wherein the first circuitry is a first
- 2 voltage level and the second circuitry is a second voltage level.
- 1 16. The semiconductor device of claim 15 wherein the first and second voltage
- 2 levels are each selected from the group consisting of Vdd, VddA, VddB, Vss, VssA,
- 3 VssB, Vref and ground.
- 1 17. The semiconductor device of claim 1 further comprising a plurality of such
- 2 ancillary electronic devices.
- 1 18. The semiconductor device as in claim 3 wherein said ancillary electronic
- 2 component is selected from the group consisting of: (a) a capacitor; (b) a resistor; (c)
- 3 an inductor; (d) a transistor; (e) a semiconductor integrated circuit; and wherein said
- 4 semiconductor device comprises an integrated circuit.
- 1 19. The semiconductor device as in claim 18 wherein said ancillary electronic
- 2 component is mounted directly on said semiconductor device.
- 1 20. An assembly comprising said semiconductor device as in claim 3 wherein said
- 2 corresponding second component comprises another plurality of electrical contact
- 3 elements connected to and extending a first distance from said corresponding second

- 4 component, said another plurality of electrical contact elements for making electrical
- 5 contact with said semiconductor device.
- 1 21. An assembly as in claim 20 wherein said corresponding second component
- 2 comprises a printed circuit board.
- 1 22. An assembly as in claim 20 wherein said corresponding second component is
- 2 arranged in a spaced apart relation to and generally parallel with said semiconductor
- 3 device.
- 1 23. An assembly as in claim 1 wherein said ancillary electronic component
- 2 comprises a travel stop structure which defines a minimum separation between a
- 3 surface of said semiconductor device and another surface.
- 1 24. A semiconductor assembly comprising:
- a semiconductor integrated circuit (IC) having interconnection pads fabricated
- on a surface of said semiconductor integrated circuit and having an
- 4 insulating layer which exposes said interconnection pads;
- 5 a first circuit element in a structure attached to said surface, said first circuit
- 6 element being coupled electrically to a second circuit element in said
- 7 semiconductor integrated circuit.
- 1 25. A semiconductor assembly as in claim 24 wherein said structure is a travel
- 2 stop structure which defines a minimum separation, between said surface and a

- 3 substrate having a contact element disposed on said substrate, in which said contact
- 4 element is electrically coupled to said semiconductor integrated circuit.
- 1 26. A semiconductor assembly as in claim 25 wherein said first circuit element
- 2 comprises a ground shield.
- 1 27. A semiconductor assembly as in claim 25 wherein said first circuit element
- 2 comprises one of (a) a capacitor; (b) a resistor; (c) a driver circuit; (d) an inductor; (e)
- 3 a shield; or (f) a routing trace.
- 1 28. A semiconductor assembly as in claim 25 wherein said structure comprises a
- 2 multilayer structure which is formed after said semiconductor IC is created.
- 1 29. A semiconductor assembly as in claim 24 wherein said first circuit element
- 2 comprises an insulated ground shield.
- 1 30. A semiconductor assembly as in claim 24 wherein said first circuit element
- 2 comprises one of (a) a capacitor; (b) a resistor, (c) a driver circlin; (d) an inductor;
- 3 (e) a shield; or (f) a routing trace.
- 1 31. A semiconductor assembly as in claim 24 wherein said structure comprises a
- 2 multilayer structure which is formed after said interconnection pads and said insulating
- 3 layer have been formed on said semiconductor IC.

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a first substrate;

1	32.	An interconnect assembly comprising:	
2		a substrate;	
3		a resilient contact element having at least a portion thereof which is capable of	
4		moving to a first position in which said resilient contact element is in	
5		mechanical and electrical contact with another contact element, said	
6		resilient contact element being disposed on said substrate;	
7		a stop structure disposed on said substrate, said stop structure defining said	
8		first position and containing a first circuit element which is coupled to a	
9		second circuit element on said substrate.	
1	33	An interconnect assembly as in claim 32 wherein said another contact element	
2	is disposed on another substrate, and wherein said stop structure defines a separation		
3	between said substrate and said another substrate in which said resilient contact		
4	eleme	nt is in mechanical and electrical contact with said another contact element.	
1	34.	An interconnect assembly as in claim 33 wherein said stop structure is	
2	disposed proximally adjacent to said resilient contact element on said substrate		
1	35.	An interconnect assembly as in claim 33 wherein said resilient contact element	
2	compr	ises a spring structure.	
1	36.	An interconnect assembly comprising:	

a first contact element disposed on said first substrate;

4	a stop structure disposed on said first substrate, said stop structure defining a
5	first position of a resilient contact element in which said resilient
6	contact element is in mechanical and electrical contact with said first
7	contact element and wherein said stop structure comprises a first circuit
8	element.

- 1 37. An interconnect assembly as in claim 36 wherein said resilient contact element
- 2 is disposed on a second substrate and wherein said resilient contact element has at
- 3 least a portion thereof which is capable of moving to said first position when said
- 4 resilient contact element is compressed.
- 1 38. An interconnect assembly as in claim 37 wherein said stop structure is
- 2 disposed proximally adjacent to said first contact element.
- 1 39. An interconnect assembly as in claim 37 wherein said first circuit element
- 2 comprises a ground shield.
- 1 40. An interconnect assembly as in claim 37 wherein said first circuit element is
- 2 coupled to a second circuit element in said first substrate.
- 1 41. An interconnect assembly comprising:
- 2 a first substrate having a first surface with first contact elements;

3	a second substrate having a second surface with second contact elements, said		
4	first surface facing said second surface and wherein a space exists		
5	between said first surface and said second surface;		
6	a plurality of interconnect elements, each respectively electrically coupling a		
7	contact element of said first contact elements to a contact element of		
8	said second contact elements;		
9	an electrical component attached to one of said first surface and said second		
10	- surface and occupying at least a portion of said space and coupled to at		
11	least one contact element of said first contact elements or said second		
12	contact elements.		
1	42. An interconnect assembly as in claim 41 wherein said first substrate comprises		
2	a semiconductor integrated circuit and wherein said plurality of interconnect elements		
3	are attached mechanically to at least one of said first substrate and said second		
4	substrate.		

- 1 43. An interconnect assembly as in claim 42 wherein said second substrate
- 2 comprises a printed circuit board and said electrical component is selected from the
- 3 group consisting of (a) a capacitor; (b) a resistor; (c) an inductor; (d) a transistor;
- 4 and (e) another semiconductor integrated circuit.
- 1 44. An interconnect assembly as in claim 41 wherein said electrical component
- 2 comprises a travel stop structure which defines a minimum separation between said
- 3 first surface and said second surface.

- 1 45. An interconnect assembly as in claim 43 wherein said plurality of interconnect
- 2 elements comprise free-standing resilient contact structures.
- 1 46. An interconnect assembly as in claim 43 wherein said plurality of interconnect
- 2 elements comprise ball structures.